

Applicant: Mid Ocean Brands B.V.

Product: CHARGING CABLE

Trademark: N/A

Model No.: MO9292

Test Standards: EN 55032:2015+A11:2020+A1:2020

EN IEC 61000-3-2:2019 +A1:2021

EN 55035:2017+A11:2020

EN 61000-3-3:2013+A2:2021+AC:2022

Test Result:

The EMC testing has been performed on the submitted

samples and found in compliance with council EMC Directive

2014/30/EU.

Approved By

Terry long

Terry Tang

Manager

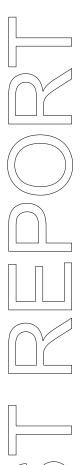
Dated: February 10, 2023

Results appearing herein relate only to the sample tested The technical reports is issued errors and omissions exempt and is subject to withdrawal at

SHENZHEN TIMEWAY TESTING LABORATORIES

Zone C, 1st Floor, Block B, Jun Xiang Da Building, Zhongshan Park Road West, Tong Le Village, Nanshan District, Shenzhen, China

Tel (755) 83448688, Fax (755) 83442996, E-Mail:info@timeway-lab.com



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Special Statement:

The testing quality ability of our laboratory meet with "Quality Law of People's Republic of China" Clause 19.

The testing quality system of our laboratory meet with ISO/IEC-17025 requirements, which is approved by CNAS. This approval result is accepted by MRA of APLAC.

Our test facility is recognized, certified, or accredited by the following organizations:

CNAS-LAB Code: L2292

The EMC Laboratory has been assessed and in compliance with CNAS-CL01 accreditation criteria for testing Laboratories (identical to ISO/IEC 17025:2017 General Requirements) for the Competence of testing Laboratories.

FCC-Registration No.: 744189

The EMC Laboratory has been registered and fully described in a report filed with the (FCC) Federal Communications commission. The acceptance letter from the FCC is maintained in our files. Registration No.: 744189.

Industry Canada (IC) —Registration No.:5205A

The EMC Laboratory has been registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 5205A.

A2LA (Certification Number: 5013.01)

The EMC Laboratory has been accredited by the American Association for Laboratory Accreditation (A2LA). Certification Number:5013.01

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4.5

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Voltage Fluctuations &Flicker Test.

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1.0 General Details

1.1 Test Lab Details

SHENZHEN TIMEWAY TESTING LABORATORIES

Zone C, 1st Floor, Block B, Jun Xiang Da Building, Zhongshan Park Road West, Tong Le Village, Nanshan

District, Shenzhen, China

Tel: +86 755 83448688 Fax: +86 755 83442996

Test Location

All tests were performed at:

SHENZHEN TIMEWAY TESTING LABORATORIES

Zone C, 1st Floor, Block B, Jun Xiang Da Building, Zhongshan Park Road West, Tong Le Village, Nanshan

District, Shenzhen, China

Tel: +86 755 83448688 Fax: +86 755 83442996

1.2 Applicant Details

Applicant: Mid Ocean Brands B.V.

Address: 7/F., Kings Tower, 111 King Lam Street, Cheung Sha Wan, Kowloon, Hong Kong.

Telephone: -Fax: --

Manufacturer: Mid Ocean Brands B.V.

Address: 7/F., Kings Tower, 111 King Lam Street, Cheung Sha Wan, Kowloon, Hong Kong.

Telephone: -Fax: --

1.3 Description of EUT

Product: CHARGING CABLE

Trademark: N/A Model Number: MO9292 Adding Trademark: N/A Adding Model Number: N/A

Rating: Input: --

Note: This is an addition test report based on original one: TW2103093E. The applicant and product name are changed, added a product image.

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1.4	Submitted	Sam	ple(s))
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1 Samples

1.5 Test Duration

Date of Receipt of Application: March 09, 2021 Date of Test: March 09, 2021 ~ February 10, 2023

1.6 Additional information of EUT

	Submitted	Not Available
User Manual	\boxtimes	
Part List		
Circuit Diagram	\boxtimes	
Printed circuit board[PCB]	\boxtimes	
Layout		
Block Diagram		

1.7 Test Engineer

Les. Lan The sample(s) tested by

Print Name: Leo Lau/ Engineer

This test report is not valid without personnel's signatures of SHENZHEN TIMEWAY TESTING LABORATORIES.

Date: 2023-02-10



2.0 List of Measurement Equipment

2.1 Conducted Emission Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EMI Test Receiver	ESCS 30	834115/006	RS	2022.07.15	1Year
LISN	NNB42	00012	SCHAFFNER	2022.08.18	1Year

2.2 Radiated Disturbance Test

				Calibration	Calibration
Name	Model No	Serial No.	Manufacturer	Date	Cycle
EMI Test Receiver	ESPI 3	100379	RS	2022.07.15	1Year
Spectrum Analyzer	E4407B	MY50441392	HP/Agilent	2022.07.15	1Year
Amplifier	BBV9743	#218	HP/Agilent	2022.07.15	1Year
Bilog Antenna	VULB9163	9163/340	Schwarebeck	2022.07.18	3Year
Horn Antenna	BBHA 9120D	9120D-631	RS	2022.07.18	3Year
Amplifier	8449B	3008A00160	HP/Agilent	2022.07.15	1Year

2.3 Harmonic & Flicker Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Harmonics Flicker Test					
System	PACS-1	72305	CI	2022.07.15	1Year
5K VA AC Power					
Source	5001iX	56060	CI	2022.07.15	N/A

2.4 ESD Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
ESD Simulator	DITO	0404-24	EM TEST	2022.07.18	1Year

2.5 RF field Strength Susceptibility

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Signal Generator	SMT03	100059	RS	2022.07.15	1Year
Power Meter	NRVS		RS	2022.07.15	1Year
Voltage Probe	URV5-Z2	100012	RS	2022.07.15	1Year

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Voltage Probe	URV5-Z2	100013	RS	2022.07.15	1Year
Power Amplifier	150W1000	300999	AR	2022.07.15	1Year
Power Amplifier	25S1G4AM1	305993	AR	2022.07.15	1Year
Field Probe	CBL6111C	2576	Holaday	2022.07.15	1Year
Bilog Antenna	MCDC		Chase	2022.07.15	1Year

2.6 Electrical Fast Transient/Burst (EFT/B) Immunity test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
EFT Generator	UCS 500 M4	0304-42	EM TEST	2022.07.15	1Year
Power Source	MV2616	0104-14	EM TEST	2022.07.15	1Year

2.7 Surge Test

					Calibration
Name	Model No.	Serial No.	Manufacturer	Calibration Date	Cycle
Ultra Compact	UCS 500				
Simulator	M4	0304-42	EM TEST	2022.07.15	1Year
Power Source	MV2616	0104-14	EM TEST	2022.07.15	1Year

2.8 Conducted Immunity Test

					Calibration	Calibration
Name		Model No.	Serial No.	Manufacturer	Date	Cycle
Continuous	Wave					
Simulator		CWS 500C	0407-05	EM TEST	2022.07.15	1 Year

2.9 Power-frequency Magnetic Field

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Continuous Wave					
Simulator	UCS 500 M4	0304-42	EM TEST	2022.07.15	1 Year
Power Source					
Network	MV 2616	0104-14	EM TEST	2022.07.15	1 Year
Current Transformer	MC2630		EM TEST	2022.07.15	1 Year
Magnetic Coil	MS100	0304-42	EM TEST	2022.07.15	1 Year

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2.10 Voltage Dips/Interruption Immunity Test

				Calibration	Calibration
Name	Model No.	Serial No.	Manufacturer	Date	Cycle
Ultra Compact					
Simulator	UCS 500 M4	0304-42	EM TEST	2022.07.15	1Year
Power Source	MV2616	0104-14	EM TEST	2022.07.15	1Year

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3.0 **Technical Details**

3.1 Investigations Requested

Perform Electromagnetic Interference [EMI] & Electromagnetic Susceptibility [EMS] tests for CE Marking

3.2 Test Standards

	Test Standards						
EN 55032:2015+A11:2020+A1:2020	Electromagnetic compatibility of multimedia equipment - Emission						
EN 33032.2013+A11.2020+A1.2020	Requirements						
	Electromagnetic compatibil	ity(EMC)- Part 3-2:Limits-Limits for					
EN IEC 61000-3-2:2019+ A1:2021	harmonic current emission	s(equipment input current ≤ 16A per					
	phase)						
	Electromagnetic compatibili	ty (EMC)- Part 3-3:Limits-Limitation of					
EN 61000-3-3:2013	voltage changes, Voltage	fluctuations and flicker in public					
+A2:2021+AC:2022	low-voltage supply systems. For equipment with rated current \leq						
	16A per phase and not subj	ect to conditional connection					
EN 55035:2017+A11:2020	Electromagnetic compatibili	ty of multimedia equipment - Immunity					
E1 33033.2017 1111.2020	requirements						
	EN 61000-4-2:2009	Electrostatic discharge					
	EN IEC 61000-4-3:2020	RF electromagnetic field disturbances					
	EN 61000-4-4:2012	Electrical Fast transients					
	EN 61000-4-5:2014	Surge					
	EN 61000-4-6:2014	Conducted susceptibility					
	EN 61000-4-8:2010	Power-frequency Magnetic Field					
	EN IEC 61000-4-11: 2020	Dips/Voltage Interruption Variation					

3.3 **Performance Criteria**

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

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3.4 **Test standards and Results Summary Tables**

Test Condition	Test Requirement	Test Method	Test Result				
EMISSION Results Summary							
Conducted Emission on AC	EN 55032:2015	EN 55032:2015	Pass				
Mains, 150kHz to 30MHz	+A11:2020+A1:2020	+A11:2020+A1:2020	Pass				
Conducted Emission on at	EN 55032:2015	EN 55032:2015					
telecommunication ports,	+A11:2020+A1:2020	+A11:2020+A1:2020	N/A				
150kHz to 30MHz							
Radiated Emissions,	EN 55032:2015	EN 55032:2015	Dana				
30MHz to 6GHz	+A11:2020+A1:2020	+A11:2020+A1:2020	Pass				
Harmonic Emissions on AC	EN IEC 61000-3-2:2019	EN IEC 61000-3-2:2019	N/A				
supply	+A1:2021	+A1:2021	IN/A				
Voltage fluctuations on AC	EN 61000-3-3:2013	EN 61000-3-3:2013	N/A				
supply	+A2:2021+AC:2022	+A2:2021+AC:2022	N/A				
	IMMUNITY Results Sumr	nary					
Electrostatic Discharge	EN 55035:2017+A11:2020	EN 61000-4-2: 2009	Pass				
Continuous RF electromagnetic	EN 55035:2017+A11:2020	EN IEC 61000-4-3:2020	Pass				
field disturbances			1 ass				
Continuous induced RF	EN 55035:2017+A11:2020	EN 61000-4-6:2014	Pass				
disturbances							
Power frequency magnetic field	EN 55035:2017+A11:2020	EN 61000-4-8: 2010	N/A				
Electrical fast transients/burst	EN 55035:2017+A11:2020	EN 61000-4-4: 2012	Pass				
(EFT/B)							
Surges	EN 55035:2017+A11:2020	EN 61000-4-5: 2014	Pass				
Voltage dips and interruptions	EN 55035:2017+A11:2020	EN IEC 61000-4-11: 2020	Pass				
Broadband impulsive conducted	EN 55035:2017+A11:2020	EN 61000-4-6:2014	NT/A				
disturbances			N/A				

Note: N/A-Not applicable

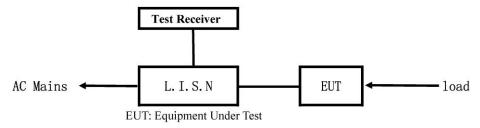
Date: 2023-02-10



4.0 Electromagnetic Interference Test results

4.1 Power line Conducted Emission Test

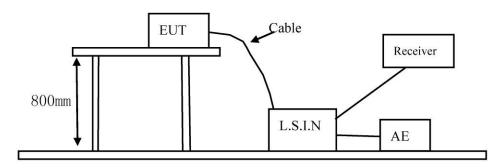
4.1.1 Schematics of the test



4.1.2 Test Method:

The test was performed in accordance with EN 55032:2015+A11:2020+A1:2020

Block diagram of Test setup



4.1.3 Power line conducted Emission Limit

	Limits dB(µ V)						
Frequency(MHz)	Class A l	Equipment	Class B Equipment				
	Quasi-peak Level	Average Level	Quasi-peak Level	Average Level			
$0.15 \sim 0.50$	79.0	66.0	66.0~56.0*	56.0~46.0*			
$0.50 \sim 5.00$	73.0	60.0	56.0	46.0			
5.00 ~ 30.00	73.0	60.0	60.0	50.0			

Notes: 1. *decreasing linearly with logarithm of frequency.

2. The lower limit shall apply at the transition frequencies

4.1.4 Test Results

Limits for Conducted Emission test, Please refer to limit line (Quasi-peak)and Average in the following diagram labelled as (QP)&AV

Remark: Calculated measurement uncertainty=3.6dB

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A: Conducted Emission on Live Terminal (150kHz to 30MHz)

EUT Operating Environment

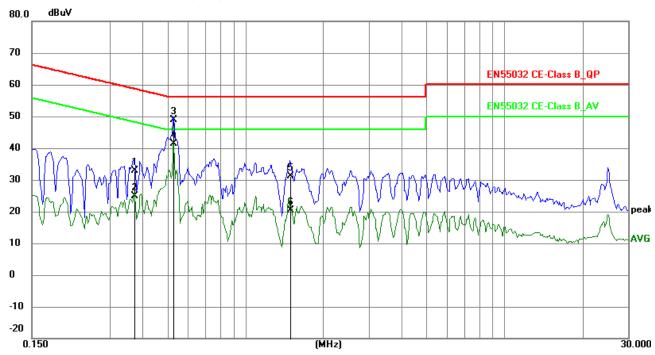
Temperature: 26°C Humidity: 65%RH Atmospheric Pressure: 101 kPa

EUT set Condition: WORKING

Equipment Level: Class B

Results: Pass

Please refer to following diagram for individual



No.	Frequency (MHz)	Reading (dBuV)	Factor (dB)	Level (dBuV)	Limit (dBuV)	Margin (dB)	Detector	P/F
1	0.3723	23.14	9.76	32.90	58.45	-25.55	QP	Р
2	0.3723	15.21	9.76	24.97	48.45	-23.48	AVG	Р
3	0.5283	39.08	9.77	48.85	56.00	-7.15	QP	Р
4	0.5283	31.63	9.77	41.40	46.00	-4.60	AVG	Р
5	1.4916	21.43	9.79	31.22	56.00	-24.78	QP	Р
6	1.4916	10.50	9.79	20.29	46.00	-25.71	AVG	Р

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B: Conducted Emission on Neutral Terminal (150kHz to 30MHz)

EUT Operating Environment

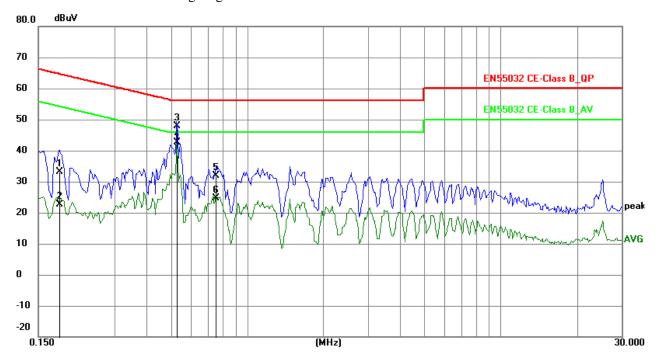
Temperature: 26°C Humidity: 65%RH Atmospheric Pressure: 101 kPa

EUT set Condition: WORKING

Equipment Level: Class B

Results: Pass

Please refer to following diagram for individual



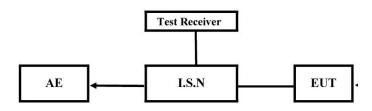
No.	Frequency (MHz)	Reading (dBuV)	Factor (dB)	Level (dBuV)	Limit (dBuV)	Margin (dB)	Detector	P/F
1	0.1812	23.49	9.76	33.25	64.43	-31.18	QP	Р
2	0.1812	12.80	9.76	22.56	54.43	-31.87	AVG	Р
3	0.5283	37.99	9.77	47.76	56.00	-8.24	QP	Р
4	0.5283	32.89	9.77	42.66	46.00	-3.34	AVG	Р
5	0.7545	22.06	9.78	31.84	56.00	-24.16	QP	Р
6	0.7545	14.95	9.78	24.73	46.00	-21.27	AVG	Р

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4.2 Telecommunication ports Conducted Emission Test

4.2.1 Schematics of the test

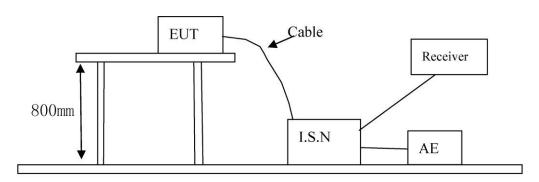


EUT: Equipment Under Test

4.2.2 Test Method:

The test was performed in accordance with EN 55032:2015+A11:2020+A1:2020

Block diagram of Test setup



4.2.3 Telecommunication ports conducted Emission Limit

	Class A Limits				Class B Limits			
Frequency(MHz)	Quasi-peak Level		Average Level		Quasi-peak Level		Average Level	
r requency (writz)	Vlotage	Current	Vlotage	Current	Vlotage	Current	Vlotage	Current
	dB(uV)	dB(uA)	dB(uV)	dB(uA)	dB(uV)	dB(uA)	dB(uV)	dB(uA)
$0.15 \sim 0.50$	97 to 87	53 to43	84 to74	40 to 30	84 to 74	40 to30	74 to64	30 to 20
0.50 ~ 30.00	87	43	74	30	74	30	64	20

Notes:

- 1. *decreasing linearly with logarithm of frequency.
- 2. The tighter limit shall apply at the transition frequencies

4.2.4 Test Results: N/A

Limits for Conducted Emission test, Please refer to limit line (Quasi-peak) and Average in the following diagram labelled as (QP)&AV

Remark:

Calculated measurement uncertainty=1.9dB

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Conducted Emission on Telecommunication port (150kHz to 30MHz)

EUT Operating Environment

Temperature: 25°C Humidity: 75 %RH Atmospheric Pressure: 101 kPa

EUT set Condition: Normal operation mode

Equipment Level: Class B

Results: N/A

Please refer to following diagram for individual

Frequency	Port	Reading(dBµV)		Limit(dBμV)	
(MHz)	Port	Quasi-peak	Average	Quasi-peak	Average

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B: Conducted Emission on Telecommunication port (150kHz to 30MHz)

EUT Operating Environment

Temperature: 25°C Humidity: 75 %RH Atmospheric Pressure: 101 kPa

EUT set Condition: Normal operation mode

Equipment Level: Class B

Results: N/A

Please refer to following diagram for individual

Frequency	Port	Reading(dBμA)	Limit(dBμA)
(MHz)	FOIT	Quasi-peak	Average	Quasi-peak	Average

Note: This test item is not applicable because there is no telecommunication port

Date: 2023-02-10



4.3 Radiated Disturbance Test

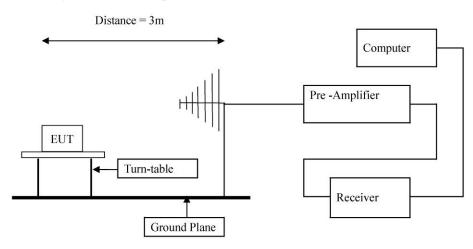
4.3.1 Schematics of the test



4.3.2 Test Method:

The test was performed in accordance with EN 55032:2015+A11:2020+A1:2020

Block diagram of Test setup



4.3.3 Radiated Disturbance Test Limit

Frequency Range (MHz)	Quasi-Peak limits (dB μ V/m)			
	Class A Limits	Class B Limi s		
0-230	50.00	40.00		
230-1000	57.00	47.00		
1000-3000	56(AV)/76(PK)	50(AV)/70(PK)		
3000-6000	60(AV)/80(PK)	54(AV)/74(PK)		

Note: The lower limit shall apply at the transition frequencies

4.3.4 Test result

Limits for Radiated Disturbance test, Please refer to limit line (Quasi-peak) in the following diagram labelled as (QP)

Remark:

Calculated measurement uncertainty=4.7dB

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Date: 2023-02-10



A: Radiated Disturbance (30MHz----1000MHz)

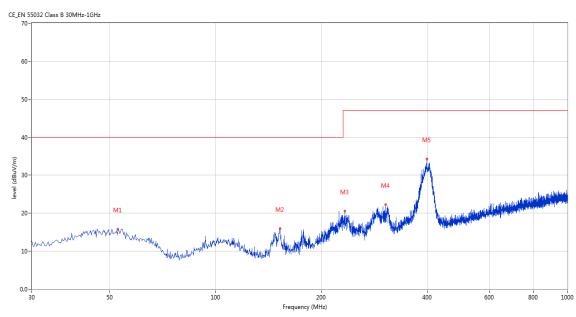
Project Number: CASE1 Test Time: 2021-03-11_13.24.01

EUT Name: CHARGING CABLE Test Engineer: HAVEN

Manufacturer: Mid Ocean Brands B.V. Test Standard: EN 55032

Model: MO9292 Work Addition: WORKING

Temp.(oC): 25 Load: Hum.: 65% Remark:



No.	Frequency	Results	Factor	Limit	Over Limit	Detector	Table (o)	Height	ANT	Verdict
	(MHz)	(dBuV/m)	(dB)	(dBuV/m)	(dB)			(cm)		
1	52.789	15.82	-11.48	40.0	-24.18	Peak	212.00	100	Horizontal	Pass
2	152.432	16.00	-16.90	40.0	-24.00	Peak	40.00	100	Horizontal	Pass
3	233.164	20.59	-12.53	47.0	-26.41	Peak	348.00	100	Horizontal	Pass
4	303.957	22.27	-10.99	47.0	-24.73	Peak	266.00	100	Horizontal	Pass
5	398.993	34.24	-8.62	47.0	-12.76	Peak	187.00	100	Horizontal	Pass

Date: 2023-02-10



B: Radiated Disturbance (30MHz----1000MHz)

Project Number: CASE1 Test Time: 2021-03-11_13.27.15

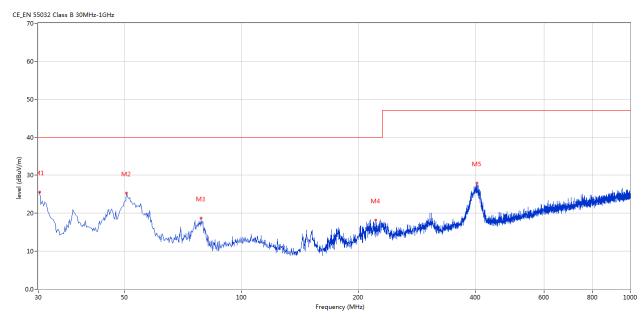
EUT Name: CHARGING CABLE Test Engineer: HAVEN

Manufacturer: Mid Ocean Brands B.V. Test Standard: EN 55032

Model: MO9292 Work Addition: WORKING

 Temp.(oC):
 25
 Load:

 Hum.:
 65%
 Remark:



No.	Frequency	Results	Factor	Limit	Over	Detector	Table (o)	Height	ANT	Verdict
	(MHz)	(dBuV/m)	(dB)	(dBuV/m)	Limit (dB)			(cm)		
1	30.242	25.52	-14.31	40.0	-14.48	Peak	252.00	100	Vertical	Pass
2	50.607	25.32	-11.39	40.0	-14.68	Peak	38.00	100	Vertical	Pass
3	78.730	18.74	-17.47	40.0	-21.26	Peak	360.00	200	Vertical	Pass
4	221.527	18.25	-13.25	40.0	-21.75	Peak	27.00	100	Vertical	Pass
5	403.599	27.89	-8.53	47.0	-19.11	Peak	92.00	100	Vertical	Pass

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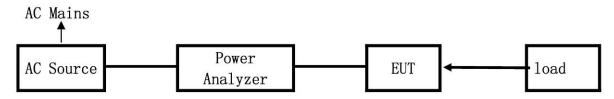
Report No.: TW2302077E

Date: 2023-02-10



4.4 **Harmonic Current Emission Test**

4.4.1 **Schematic of the test**



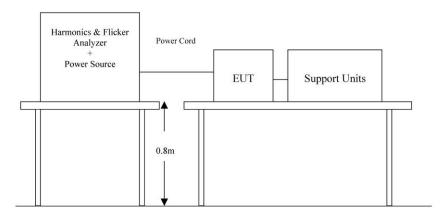
EUT: Equipment Under Test

4.4.2 Test Method:

The test was performed in accordance with EN IEC 61000-3-2:2019 +A1:2021

*: The Level of the product is : CLASS D

Block diagram of Test setup



4.4.3 Limits of Harmonic Current Emission For Class A

Date: 2023-02-10



Harmonic order	Maximum permissible harmonic current			
n	A			
Odd har	monics			
3	2,30			
5	1,14			
7	0,77			
9	0,40			
11	0,33			
13	0,21			
15 ≤ n ≤ 39	0,15 1 <u>5</u>			
Even har	monics			
2	1,08			
4	0,43			
6	0,30			
8 ≤ n ≤ 40	0,23 <u>8</u>			

4.4.4 Test Results

Please refer to the following pages

Harmonic Current Emission Test

EUT Operating Environment

Temperature: 25°C Humidity: 53%RH Atmospheric Pressure: 101 kPa

EUT set Condition:

Results: N/A

N/A --- DC Operation.

Please refer to following diagram for individual

Harmonic results as a% of the limits

No	(Test	No	(Test	No	(Test	No	(Test
	result/Limit)%		res lt/Limit)%		result/Limit)%		result/Limit)%
1		11		21		31	
2		12		22		32	
3		13		23		33	
4		14		24		34	
5		15		25		35	
6		16		26		36	
7		17		27		37	
8		18		28		38	
9		19		29		39	
10		20		30		40	

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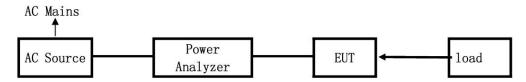
Report No.: TW2302077E

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4.5 Voltage Fluctuations & Flicker Test

4.5.1 Schematic of the test

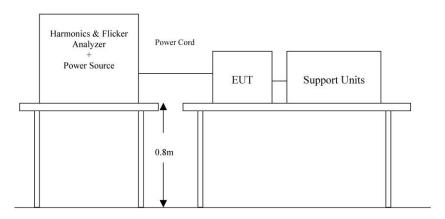


EUT: Equipment Under Test

4.5.2 Test Method:

The test was performed in accordance with EN 61000-3-3:2013+A2:2021+AC:2022

Block diagram of Test setup



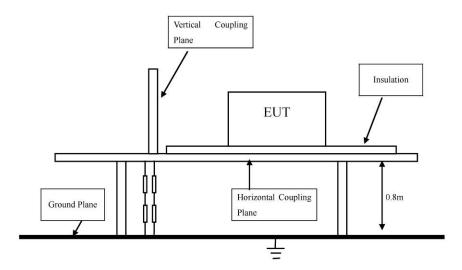
4.5.3 Test Results

Result: N/A

Date: 2023-02-10



- 5.0 Immunity Test
- 5.1 Electrostatic Discharge
- 5.1.1 Schematic of the test



5.1.2 Test method

The test was performed in accordance with EN 61000-4-2: 2009

5.1.3 Test severity

±4kV for direct & in-direct Contact Discharge

±8kV for air Discharge

Performance Criterion Require: **B** (Please see following table)

5.1.4 Susceptibility performance Criteria and Severity level

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

Level	Test Voltage Direct & in-direct contact	Test Voltage Air
	Discharge (kV)	discharge(kV)
1	$\pm 2 \mathrm{kV}$	±2kV
2	$\pm 4 \mathrm{kV}$	±4kV
3	$\pm 6 \mathrm{kV}$	$\pm 8 \mathrm{kV}$
4	$\pm8\mathrm{kV}$	$\pm 15 \mathrm{kV}$

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5.1.5 Test Result

EUT Operating Environment

Temperature: 25 °C Humidity: 53%RH Atmospheric Pressure: 101 kPa

Please refer to the following table for individual results.

Location	Discharge Method	Test Voltage	Results
HCP (Horizontal coupling plane)	In-Direct	$\pm 2kV, \pm 4kV$	Pass
VCP (Vertical Coupling plane)	In-Direct	$\pm 2kV, \pm 4kV$	Pass
USB Port	Contact Discharge	$\pm 2kV, \pm 4kV$	Pass
Enclosure	Air Discharge	$\pm 2kV, \pm 4kV, \pm 8kV$	Pass

Remark: Calculated measurement uncertainty= 0.2kV

Date: 2023-02-10



5.2 RF field strength susceptibility (80MHz-1000MHz, 1800MHz, 2600MHz, 3500MHz, 5000MHz)

5.2.1 Schematics of the test



EUT: Equipment Under Test

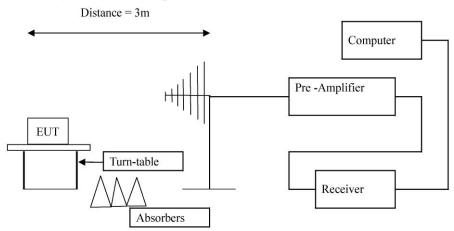
5.2.2 Test Method:

The test was performed in accordance with EN IEC 61000-4-3:2020

Severity: Level 2 (3V/m) Modulation: 80% AM

Performance Criterion Require: A (Please see following table)

Block diagram of Test setup



5.2.3 Susceptibility performance Criteria and severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

Level	Field Strength (V/m)
1	1
2	3
3	10

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5.2.4 Test Result:

EUT Operating Environment

Temperature: 25 °C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following table for individual results.

Frequency	Face	Polarity	Level	Dwell	Sweep	Results
(MHz)			(V/m)	Time(s)	Rate (%)	
80-1000	0°	Horizontal	3	1	1	Pass
80-1000	90°	Horizontal	3	1	1	Pass
80-1000	180°	Horizontal	3	1	1	Pass
80-1000	270°	Horizontal	3	1	1	Pass
80-1000	0°	Vertical	3	1	1	Pass
80-1000	90°	Vertical	3	1	1	Pass
80-1000	180°	Vertical	3	1	1	Pass
80-1000	270°	Vertical	3	1	1	Pass
1800,	0°	Horizontal	3	1	1	Pass
2600,	90°	Horizontal	3	1	1	Pass
3500,	180°	Horizontal	3	1	1	Pass
5000	270°	Horizontal	3	1	1	Pass
1800,	0°	Vertical	3	1	1	Pass
2600,	90°	Vertical	3	1	1	Pass
3500,	180°	Vertical	3	1	1	Pass
5000	270°	Vertical	3	1	1	Pass

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5.3 Electrical Fast Transient/Burst (EFT/B) immunity test

5.3.1 Schematics of the test



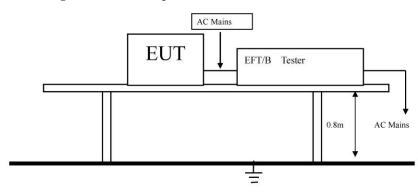
5.3.2 Test Method

The test was performed in accordance with EN 61000-4-4:2012

Severity: Level 2 (1kV)

Performance Criterion Require: **B** (Please see following table)

Block diagram of Test setup



5.3.3 Susceptibility performance Criteria and Severity Level

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

	Open Circuit output Test Voltage	$\pm 10\%$
Level	On power Supply Lines	On I/O (Input/output)
		Signal data and control lines
1	0.5kV	0.5kV
2	1kV	1kV
3	2kV 2kV	
4	4kV 4kV	
X	Special	Special

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5.3.4 Test Results

EUT Operating Environment

Temperature: 25 °C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following table for individual results.

Inject location: AC mains

Inject Line	Voltage	Inject	Method	Results
	kV	Times (s)		
L	±1	120	Direct	Pass
N	±1	120	Direct	Pass
L-N	±1	120	Direct	Pass

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5.4 Surge test

5.4.1 Schematics of the test



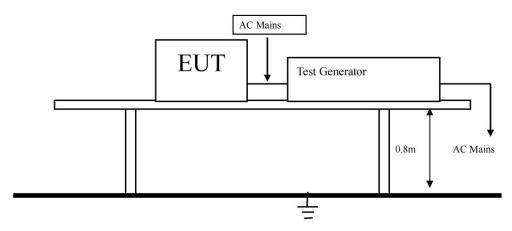
5.4.2 Test Method:

The test was performed in accordance with EN 61000-4-5:2014

Severity: Level 2 (Line to Neutral at 1kV)

Performance Criterion Require: B (Please see following table)

Block diagram of Test setup



5.4.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
B Degradation of performance allowed during the test the EUT returning intended operation after the test.	
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

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Severity Level

Severity Level	Open-Circuit Test Voltage	
	kV	
1	0.5	
2	1.0	
3	2.0	
4	4.0	
*	Special	

5.4.4 Test Results

EUT Operating Environment

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following table for individual results.

Test location:

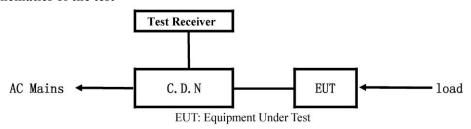
Location	Polarity	Phase	No of	Pulse	Results
		Angle	Pulse	Voltage(kV)	
	±	0	5	1.0	Pass
LNI	±	90	5	1.0	Pass
L-N	±	180	5	1.0	Pass
	±	270	5	1.0	Pass

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5.5 Conducted Immunity test

5.5.1 Schematics of the test



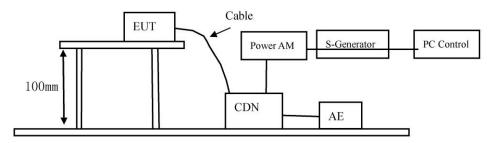
5.5.2 Test Method

The test was performed in accordance with EN 61000-4-6:2014

Severity: Level 2 (3 V rms),0.15MHz—80MHz

Performance Criterion Require: A (Please see following table)

Block diagram of Test setup



5.5.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

Severity Level	Voltage Level (e.m.f) V
1	1
2	3
3	10
*	Special

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5.5.4 Test Results:

EUT Operating Environment

Temperature: 25 °C Humidity: 75%RH Atmospheric Pressure: 101 KPa

Please refer to the following table for individual results.

Frequency	Injected Position	Strength	Criterion	Result
Range (MHz)				
0.15 - 10	AC Line	3V (rms)	A	Pass
10 - 30	AC Line	3 to 1V (rms)	A	Pass
30-80	AC Line	1V (rms)	A	Pass

Note: the amplitude of a test level varies over a given frequency range, it changes linearly with respect to the logarithm of the frequency

Date: 2023-02-10



5.6 Power-Frequency magnetic field test

5.6.1 Schematics of the test



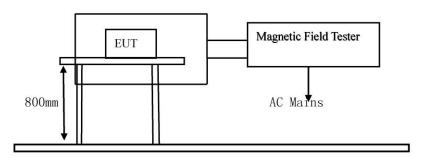
5.6.2 Test Method

The test was performed in accordance with EN 61000-4-8:2010

Severity: Level 1 (1A/m),

Performance Criterion Require: A (Please see following table)

Block diagram of Test setup



5.6.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
B Degradation of performance allowed during the test the EUT returning intended operation after the test.	
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

Severity Level

Severity Level	Magnetic Field Strength A/m
1	1
2	3
3	10
4	30
5	100
*	Special

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5.6.4 Test Results:

EUT Operating Environment

Temperature: 25 °C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following table for individual results.

Test Level	Testing Duration	Coil Orientation	Criterion	Result
1A/m	5 Mins	X	A	N/A
1A/m	5 Mins	Y	A	N/A
1A/m	5 Mins	Z	A	N/A

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5.7 Voltage Dips/Interruptions immunity test

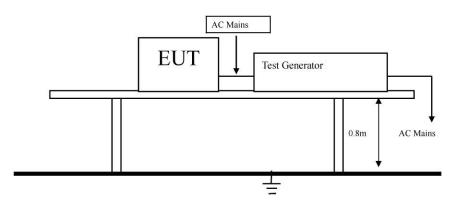
5.7.1 Schematics of the test



5.7.2 Test Method:

The test was performed in accordance with EN IEC 61000-4-11: 2020 Performance Criterion Require: C&B (Please see following table)

Block diagram of Test setup



5.7.3 Susceptibility performance Criteria and Severity Level

Susceptibility performance Criteria

Criterion	Description
A	No change in operational mode or degradation of performance outside of specification and no change in stored parameters.
В	Degradation of performance allowed during the test the EUT returning to intended operation after the test.
C	Loss of function allowed during the test, provided that function is self recoverable or can be recovered by operation of controls.

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Severity Level

Voltage Dip	Test Level %Ut	Reduction	Duration	Performance			
			(Periods)	Criteria			
	<5	>95	0.5	В			
	70	30	25	С			
Voltage Interceptions	Test Level %Ut	Reduction	Duration	Performance			
			(Periods)	Criteria			
	<5	>95	250	C			

5.7.4 Test Result:

EUT Operating Environment

Temperature: 25°C Humidity: 75%RH Atmospheric Pressure: 101 kPa

Please refer to the following table for individual results.

Voltage Dip:

Test Level	Reduction	Duration	Phase Angle	Meet	Result
% Ut		(periods)		Criterion	
0	100	0.5	0° -360°	В	Pass
70	30	25	0° -360°	С	Pass

Voltage Interceptions:

Test Level % Ut	Reduction	Duration (periods)	Phase Angle	Meet Criterion	Result
0	100	250	0° - 360°	С	Pass

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6.0 Product Labelling

6.1 CE Mark label specification

Text of the mark is black or white in color and is left justified. Labels are printed in indelible ink on permanent adhesive backing and shall be affixed at a conspicuous location on the EUT or silk-screened onto the EUT.



6.2 Mark Location: Rear enclosure

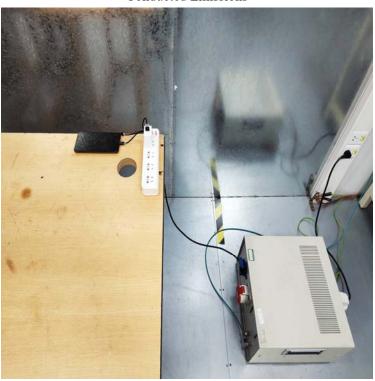
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Appendix:

Conducted Emissions

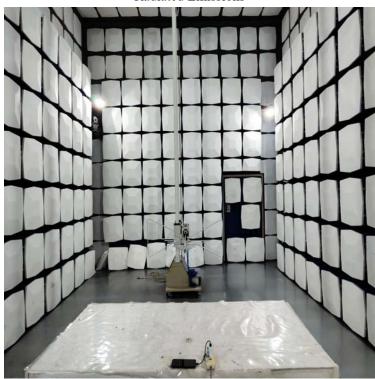


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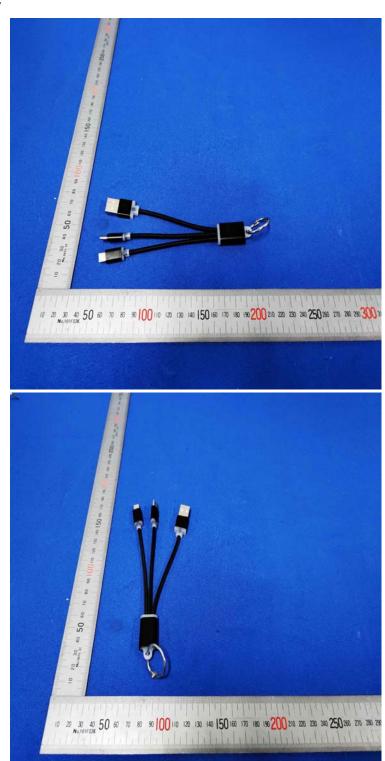
Radiated Emissions



Date: 2023-02-10



Photo for the EUT



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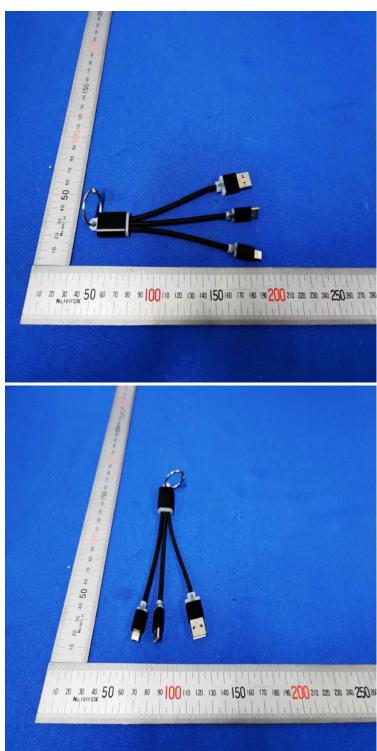
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Photo for the EUT





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